


<b>Search Notes</b> 	<b>Application/Control No.</b> 10765870	<b>Applicant(s)/Patent Under Reexamination</b> INON, GAD
	<b>Examiner</b> Gauthier, Gerald	<b>Art Unit</b> 2614

SEARCHED			
Class	Subclass	Date	Examiner
379	88.22	1/18/2007	GG
348	14.06	1/18/2007	GG
707	104.1	1/18/2007	GG
709	224	1/18/2007	GG
455	412.1	6/4/2007	GG
709	205	3/4/2008	GG
379	88.13, 88.17, 88.22	8/20/2008	GG
455	451	8/20/2008	GG
709	228	8/20/2008	GG

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB)	8/28/2006	GG
EAST (US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB)	1/18/2007	GG
EAST (US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB)	6/4/2007	GG
EAST (US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB)	3/4/2008	GG
EAST (US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB)	8/20/2008	GG

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

	/Gerald Gauthier/ Primary Examiner.Art Unit 2614
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